


**PRODUCT / PROCESS CHANGE NOTIFICATION**

**1. PCN basic data**

<b>1.1 Company</b>		STMicroelectronics International N.V
<b>1.2 PCN No.</b>	POWER AND DISCRETE PRODUCTS/25/15161	
<b>1.3 Title of PCN</b>	Qualification of the new Lead Frame and soft solder dispenser tool for selected MOSFET LV products in TO252 (DPAK) in TFME plant.	
<b>1.4 Product Category</b>	Pls Refer to the Products List (MOSFET LV)	
<b>1.5 Issue date</b>	2025-01-14	

**2. PCN Team**

<b>2.1 Contact supplier</b>
-----------------------------

**3. Change**

<b>3.1 Category</b>	<b>3.2 Type of change</b>	<b>3.3 Manufacturing Location</b>
Materials	New direct material part number r (same supplier, different supplier or new supplier),(Lead frame dimensions)	998G (TFME)

**4. Description of change**

	<b>Old</b>	<b>New</b>
<b>4.1 Description</b>	Standard DPAK Leadframe TO252-3H + Soft Solder dispenser PUM.	New DPAK Leadframe TO252-3U + Soft Solder dispenser SPANKER.
<b>4.2 Anticipated Impact on form,fit, function, quality, reliability or processability?</b>	No Impact	

**5. Reason / motivation for change**

<b>5.1 Motivation</b>	To continuously improve our service and to rationalize and optimize Power MOSFET Transistors productivity.
<b>5.2 Customer Benefit</b>	SERVICE IMPROVEMENT

**6. Marking of parts / traceability of change**

<b>6.1 Description</b>	Dedicated FGs
------------------------	---------------

**7. Timing / schedule**

<b>7.1 Date of qualification results</b>	2024-12-20
<b>7.2 Intended start of delivery</b>	2025-04-01
<b>7.3 Qualification sample available?</b>	Upon Request

**8. Qualification / Validation**

<b>8.1 Description</b>	15161 RERLVIP24034_1.0_New_LF_TO252-3U_Die_attached_Spanker_DPAK_TFME.pdf		
<b>8.2 Qualification report and qualification results</b>	Available (see attachment)	<b>Issue Date</b>	2025-01-14

**9. Attachments (additional documentations)**

15161 Public product.pdf  
15161 New Lead Frame and soft solder tool for LV in TO252 (DPAK) in TFME plant .pdf  
15161 RERLVIP24034\_1.0\_New\_LF\_TO252-3U\_Die\_attached\_Spanker\_DPAK\_TFME.pdf

10. Affected parts		
10.1 Current		10.2 New (if applicable)
10.1.1 Customer Part No	10.1.2 Supplier Part No	10.1.2 Supplier Part No
	STD20NF20	
	STD60NF06T4	

**IMPORTANT NOTICE – PLEASE READ CAREFULLY**

Subject to any contractual arrangement in force with you or to any industry standard implemented by us, STMicroelectronics NV and its subsidiaries (“ST”) reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST’s terms and conditions of sale in place at the time of order acknowledgement.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers’ products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2022 STMicroelectronics – All rights reserved



life.augmented

## Public Products List

Public Products are off the shelf products. They are not dedicated to specific customers, they are available through ST Sales team, or Distributors, and visible on ST.com

**PCN Title :** Qualification of the new Lead Frame and soft solder dispenser tool for selected MOSFET LV products in TO252 (DPAK) in TFME plant.

**PCN Reference :** POWER AND DISCRETE PRODUCTS/25/15161

**Subject :** Public Products List

Dear Customer,

Please find below the Standard Public Products List impacted by the change.

STD60NF06T4	STD40NF10	STD20NF20
-------------	-----------	-----------

**IMPORTANT NOTICE – PLEASE READ CAREFULLY**

Subject to any contractual arrangement in force with you or to any industry standard implemented by us, STMicroelectronics NV and its subsidiaries (“ST”) reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST’s terms and conditions of sale in place at the time of order acknowledgement.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers’ products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.



life.augmented

**Qualification of the new Lead Frame and soft solder dispenser tool for the Mosfet products in TO252 (DPAK) package in TFME plant :  
STD60NF06T4, STD40NF10 and STD20NF20**

# Agenda

3 Change Description

7 Product lines impacted

4 Lead Frame  
Comparison

8 BOM Comparison

6 Soft Solder dispenser tool  
Comparison

9 Conclusion

# Change description

- Aim of this document is to describe following qualification activity performed for the STD60NF06T4, STD40NF10 and STD20NF20 Mosfet products in TO252 (DPAK) package in TFME plant :
  - new Lead Frame with large die pad → from current TO252-3H to new TO252-3U lead frame
  - New soft solder dispenser tool → from current PUM to new SPANKER
- This report shows the qualification plan that ensures the same quality and electrical characteristics of these 3 product lines currently in production in the TO252 (DPAK) in the TFME plant.
- All reliability tests have been completed with positive results.

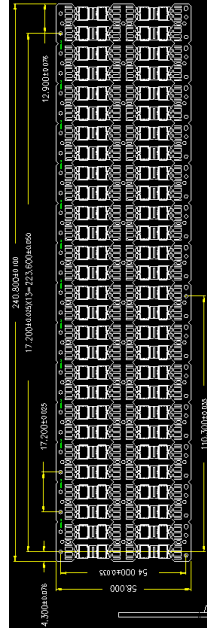
# Lead Frame comparison current TO252-3H vs new TO252-3U

Comparing the actual standard lead frame TO252-3H (Shinwon supplier) with new the TO252-3U (SDI and Jieliin suppliers):

- Both SDI and Jieliin supplier were qualified for ST product;
- The strip level drawing of TO252-3U from Jieliin is same as SDI;

Lead frame (strip level):

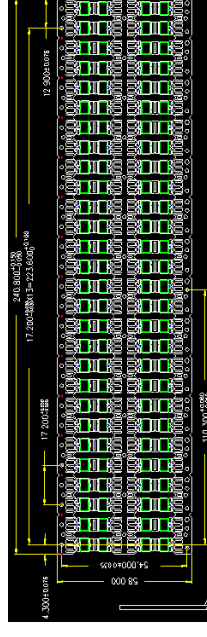
Item	TO252-3H (current)	TO252-3U (New)	from SDI	TO252-3U (New)	from Jieliin
Supplier	Shinwon	SDI		Jieliin	
Copper type	HCL-12SN	TAMAC4		HCL-12SN	
Manufacture Method	Stamping	Stamping		Stamping	
LF SIZE L×W×T	240.8*58*0.5(0.8)	240.8*58*0.5(0.8)		240.8*58*0.5(0.8)	
Matrix	112units(4*28)	112units(4*28)		112units(4*28)	
Location hole spacing	17.2+/-0.025mm	17.2+/-0.025mm		17.2+/-0.025mm	



Current  
TO252-3H



New  
TO252-3U

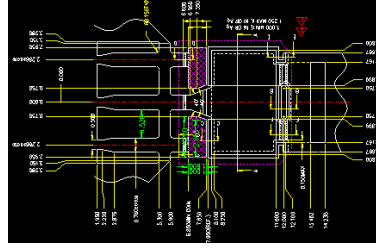


# Lead Frame comparison current TO252-3H vs new TO252-3U

Comparing the actual standard lead frame TO252-3H (Shinwon supplier) with new the TO252-3U (SDI and Jielin suppliers):

Lead frame (unit level):

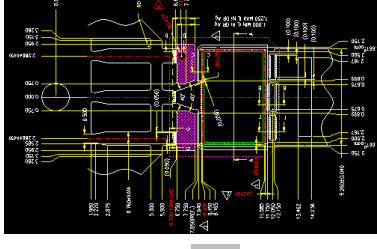
Item	TO252-3 (current)	TO252-3U from SDI (new)	TO252-3U from Jielin (new)	note
Plating Method	Spot Ni, plating on inner lead	Spot Ni, plating on inner lead	Spot Ni, plating on inner lead	
Plating thickness	1.3um~3.5um	1.3um~3.5um	1.3um~3.5um	
Die pad	Size	Size :5.6*3.5mm	Size :5.5*3.81mm(inner v-groove: 5.04*3.29mm)	TO252-3U can meet the max single die size of mass production. Increased Y-direction size in order to follow the design rule of big die attached with spanker.
	Design	No V-groove	V-groove on each sides	Add V-groove can improve overflow.
Inner lead Design	1.Size:2.2*1.0mm 2.No Mold-lock	1.Size:2.2*1.0mm 2.Mold-lock on Pin1	1.Size:2.2*1.0mm 2.Mold-lock on Pin1	Add mold lock can improve the Delam on inner lead.
Outside lead pitch	2.286±0.03mm	2.286±0.03mm	2.286±0.03mm	
Outside lead width	0.76±0.03mm	0.76±0.03mm	0.76±0.03mm	



Current  
TO252-3H



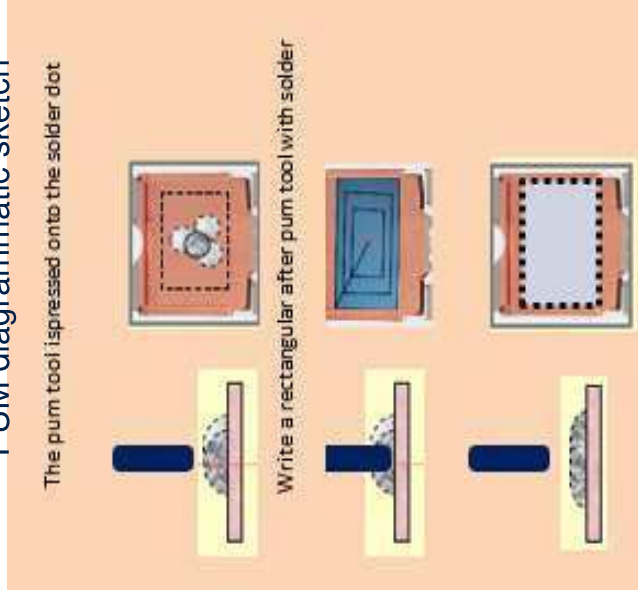
New  
TO252-3U



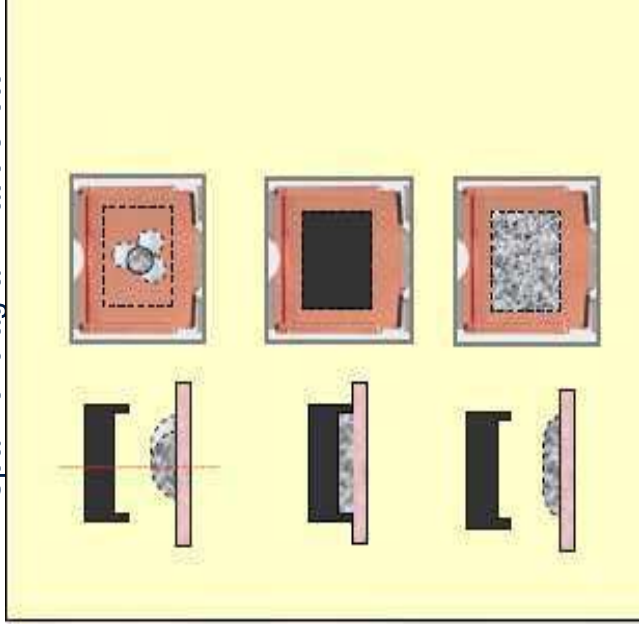
# Soft Solder dispenser tool comparison current PUM vs new SPANKER

Comparing the actual PUM and spanker

PUM diagrammatic sketch



Spanker diagrammatic sketch



# Product lines impacted

The products lines impacted & qualified in TFME subcontractor plant

## MOSFET Products lines in DPACK (DP package codes)

Commercial Product :	STD60NF06T4	(Silicon Line ED6F01)
Commercial Product :	STD40NF10	(Silicon Line MM0G01)
Commercial Product :	STD20NF20	(Silicon Line MM2G01)

# Bill Of Material Comparison

Actual Bill of Material in TFME	
ITEM	MATERIAL
FRAME	TO-252-3H(IL Ni) - DWG#: TO-LFM-SW005
DIE ATTACH	SOFT SOLDER Pb/Ag/Sn 95.5/2.5/2
MOLD COMPOUND	RESIN EME-G620A
WIRE	Al 10 mils
WIRE	Al 5 mils



New Bill of Material in TFME	
ITEM	MATERIAL
FRAME	TO-LFM-HI015 and SD079 Rev4
DIE ATTACH	SOFT SOLDER Pb/Ag/Sn 95.5/2.5/2
MOLD COMPOUND	RESIN EME-G620A
WIRE	Al 10 mils
WIRE	Al 5 mils

# Conclusions

- Detailed activity has been performed in order to qualify the new Lead Frame with large die pad and new soft solder dispenser tool for the STD60NF06T4, STD40NF10 and STD20NF20 Mosfet products in TO252 (DPAK) package in TFME plant.
- All reliability tests have been completed with positive results.
- This report shows the positive results achieved, ensuring the same quality and electrical characteristics as the current production in TFME plant.



## Reliability Evaluation Report

RERLVIP24034

New lead frame TO252-3U / Die attached method Spanker

DPAK - Tongfu TFME (China) subcon

PowerMOSFET Planar and EHD2 Technology

Release	Date	Author	Function
1.0	September 24 <sup>th</sup> , 2024	A. Giuffrida	APMS – Q&R - Catania

This report is a summary of the reliability trials performed in good faith by STMicroelectronics. This report does not imply for STMicroelectronics expressly or implicitly any contractual obligations other than as set forth in STMicroelectronics General Terms and Conditions of Sale.

## RELIABILITY EVALUATION OVERVIEW

- **OBJECTIVE**

Aim of this report is to present the reliability evaluations performed on **STD60NF06T4, STD40NF10, STD20NF20** (respectively ED6F, MM0G and MM2G as ST internal silicon line) chosen as test vehicles to qualify the new lead frame TO252-3U and the new die attached method Spanker for PowerMOSFET Low Voltage products designed in EHD2 and Planar Technology, assembled in package DPAK in Tongfu TFME (China) subcon Assembly Plant.

- **CONCLUSION**

All reliability tests have been completed with positive results. Neither functional nor parametric rejects were detected at final electrical testing.

Based on the overall results obtained, the new lead frame TO252-3U and the new die attached method Spanker for PowerMOSFET Low Voltage products designed in EHD2 and Planar Technology, assembled in package DPAK in Tongfu TFME (China) subcon Assembly Plant, have positively passed reliability evaluation performed in agreement with **ST 0061692** specification.

**TABLE OF CONTENTS**

- 1. RELIABILITY STRATEGY .....4
  - 1.1. RELIABILITY STRATEGY.....4
  - 1.2. TEST PLAN .....4
  - TABLE 1 – TEST PLAN .....4
- 2. PRODUCT OR TEST VEHICLE CHARACTERISTICS .....5
  - 2.1. GENERALITIES .....5
  - 2.2. PIN CONNECTION / BONDING DIAGRAM .....6
  - 2.3. TRACEABILITY .....7
    - 2.3.1. WAFER FAB INFORMATION .....7
    - 2.3.2. ASSEMBLY PLANT INFORMATION .....7
    - 2.3.3. RELIABILITY TESTING INFORMATION .....7
- 3. TEST RESULTS SUMMARY .....8
  - 3.1. LOT INFORMATION .....8
  - 3.2. ACCELERATED ENVIRONMENT STRESS TESTS .....8
  - 3.3. ACCELERATED LIFETIME SIMULATION TESTS .....8
  - 3.4. ELECTRICAL VERIFICATION TESTS .....8
- 4. REVISION HISTORY .....9
- TERMS OF USE .....10

## 1. RELIABILITY STRATEGY

### 1.1. Reliability strategy

To evaluate the introduction of the new frame TO252-3U and the new die attached method Spanker for PowerMOSFET Low Voltage products designed in EHD2 and Planar Technology, assembled in package DPAK in Tongfu TFME (China) subcon Assembly Plant, the qualification plan was based to address the specific failure mechanism on 3 different chosen test vehicles.

Reliability trials performed as part of this reliability evaluation are in agreement with **ST 0061692** specification and are listed in below Test Plan. For details on test conditions, generic data used and specifications references, refer to test results summary in section 3.

### 1.2. Test Plan

Table 1 – TEST PLAN

TEST	TEST NAME	DESCRIPTION / COMMENTS	TEST FLAG
ACCELERATED ENVIRONMENT STRESS	PC	Preconditioning	Yes
	H <sup>3</sup> TRB	High Humidity High Temp. Reverse Bias	Yes
	AC	Autoclave	Yes
	TC	Temperature Cycling	Yes
	IOL	Intermittent Operational Life	Yes
ACCELERATED LIFETIME SIMULATION	HTRB	High Temperature Reverse Bias	No
	HTGB	High Temperature Gate Bias	No
ELECTRICAL VERIFICATION	TEST	Pre- and Post-Stress Electrical Test	Yes
	PV	Parametric Verification	No
	EV	External Visual	Yes
	ESDH (HBM)	ESD HBM Characterization	No
	ESDC (CDM)	ESD CDM Characterization	No

Reliability Evaluation Report

## 2. PRODUCT OR TEST VEHICLE CHARACTERISTICS

### 2.1. Generalities

**STD20NF20**  
**STF20NF20, STP20NF20**

N-channel 200 V, 0.10 Ω, 18 A DPAK, TO-220, TO-220FP  
low gate charge STripFET™ Power MOSFET

**Features**

Type	V <sub>GS</sub>	R <sub>DS(on)</sub>	I <sub>C</sub>	P <sub>tot</sub>
STD20NF20	200 V	~ 0.125 Ω	18 A	110 W
STF20NF20	200 V	~ 0.125 Ω	18 A	30 W
STP20NF20	200 V	~ 0.125 Ω	18 A	110 W

- Exceptional dv/dt capability
- Low gate charge
- 100% avalanche tested

**Application**

- Switching applications

**Description**

This Power MOSFET series realized with STMicroelectronics unique STripFET™ process has specifically been designed to minimize input capacitance and gate charge. It is therefore suitable as primary switch in advanced high-efficiency isolated DC-DC converters.

**Figure 1. Internal schematic diagram**

**Table 1. Device summary**

Order codes	Marking	Package	Packaging
STD20NF20	20NF20	DPAK	Tape and reel
STF20NF20	20NF20	TO-220FP	Tube
STP20NF20	20NF20	TO-220	Tube

**STD40NF10**

Datasheet

N-channel 100 V, 25 mΩ typ., 50 A, STripFET™ II Power MOSFET in a DPAK package

**Features**

Type	V <sub>GS</sub>	R <sub>DS(on)</sub> max.	I <sub>C</sub>
STD40NF10	100 V	25 mΩ	50 A

- Exceptional dv/dt capability
- 100% avalanche tested
- Low gate charge

**Applications**

- Switching applications

**Description**

This Power MOSFET series has been developed using STMicroelectronics' unique STripFET™ process, which is specifically designed to minimize input capacitance and gate charge. This renders the device suitable for use as primary switch in advanced high-efficiency isolated DC-DC converters for telecom and computer applications, and applications with low gate charge driving requirements.

**Product status link**

STD40NF10

**Product summary**

Order code	Marking	Package	Packing
STD40NF10	D40NF10	DPAK	Tape and reel

**STD60NF06T4**

Datasheet

N-channel 60 V, 0.014 Ω typ., 60 A STripFET™ II Power MOSFET in a DPAK package

**Features**

Order code	V <sub>GS</sub>	R <sub>DS(on)</sub> max.	I <sub>C</sub>
STD60NF06T4	60 V	0.014 Ω	60 A

- Exceptional dv/dt capability
- 100% avalanche tested
- Low gate charge

**Applications**

- Switching applications

**Description**

This Power MOSFET series has been developed using STMicroelectronics' unique STripFET™ process, which is specifically designed to minimize input capacitance and gate charge. This renders the device suitable for use as primary switch in advanced high-efficiency isolated DC-DC converters for telecom and computer applications, and applications with low gate charge driving requirements.

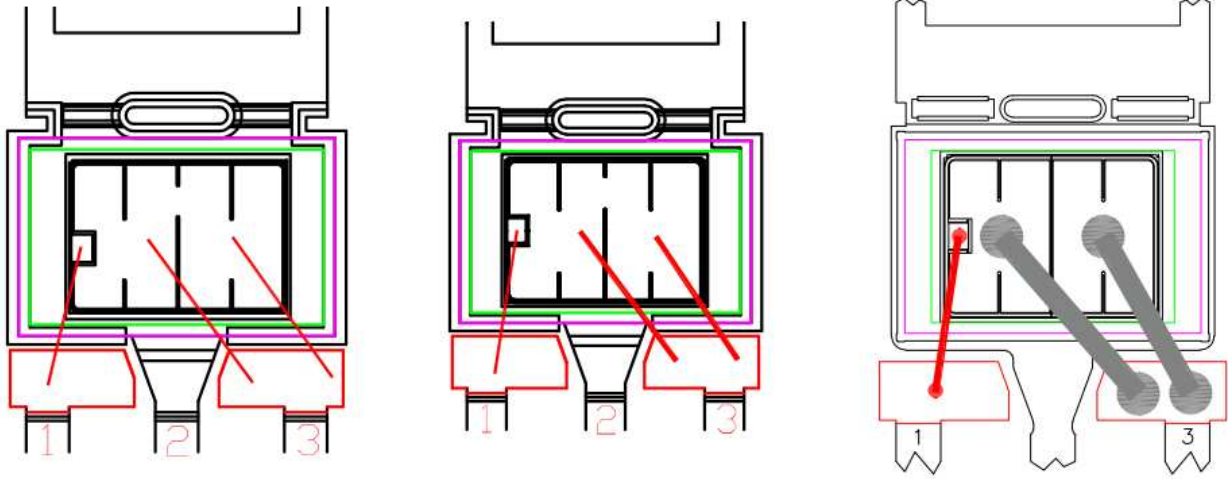
**Product status link**

STD60NF06T4

**Product summary**

Order code	Marking	Package	Packing
STD60NF06T4	D60NF06	DPAK	Tape and reel

2.2. Pin connection / Bonding diagram



## 2.3. Traceability

## 2.3.1. Wafer Fab information

Wafer fab information	
Wafer Fab name / location	Ang Mo Kio SG6 (Singapore)
Wafer diameter (inches)	6"
Wafer thickness (µm)	280 µm
Silicon process technology	EHD2 PLANAR
Die finishing front side	(ED6F/MM0G) No Passivation (MM2G) SiN (nitride)
Die finishing back side	(ED6F/MM0G) Ti-Ni-Au (MM2G) Ti-Ni_Ag
Die size	(ED6F) 2900 x 3780 µm (MM0G) 2920 x 3960 µm (MM2G) 2920 x 3980 µm
Metal levels/Materials/Thicknesses	(ED6F) AlSi 4.5 µm (MM0G/MM2G) AlSiCu 4.5 µm

## 2.3.2. Assembly Plant information

Assembly Information	
Assembly Plant name / location	Tongfu – TFME (China) subcon
Package description	DPAK
Lead frame	TO252-3U
Die attach	SOFT SOLDER Pb/Ag/Sn 95.5/2.5/2
Wire bonding	Al 5 mils Al 10 mils
Molding compound	RESIN EME-G620A
Package Moisture Sensitivity Level (J-STD020D)	MSL1

## 2.3.3. Reliability testing information

Reliability Testing Information	
Reliability laboratory location	ST Catania

Note: ST is ISO 9001 certified. This induces certification of all internal and subcontractor labs. ST certification document can be downloaded under the following link:  
[http://www.st.com/content/st\\_com/en/support/quality-and-reliability/certifications.html](http://www.st.com/content/st_com/en/support/quality-and-reliability/certifications.html)

### 3. TEST RESULTS SUMMARY

#### 3.1. Lot Information

Lot #	Commercial Product	Diffusion Lot	Assy lot	comment
1	STD60NF06T4 (ED6F)	V6320JK3	GF328476	EHD2 Technology
2	STD40NF10 (MM0G)	V6310H93	GF328474	Planar Technology
3	STD20NF20 (MM2G)	V632112L	GF328475	Planar Technology

#### 3.2. ACCELERATED ENVIRONMENT STRESS TESTS

Test	Reference	STM Test Conditions	Lots	S.S.	Total	Results FAIL/SS/Lots	Comments
PC	JEDEC/IPC J-STD-020 JESD22-A-113	MSL1 (168h@85C/85%RH) 3x Reflow simulation Peak Reflow Temp= 260°C	3	308	924	0/308/3	All parts before H <sup>3</sup> TRB, AC, TC, IOL
H <sup>3</sup> TRB	JESD22A-101	1000h @ Ta=85°C, RH=85% Vds=100V and 60V	3	77	231	0/77/3	1 lot / vehicle  100V for Planar 60V for EHD2
AC	JESD22 A-102	ES (Environmental Sequence) 100cy @ T= -55°C/+150°C 96h @ T= 121°C, 2atm, 100%RH	3	77	231	0/77/3	1 lot / vehicle
TC	JESD22A-104	1000cy @ Ta=-55°C /+150°C	3	77	231	0/77/3	1 lot / vehicle
IOL	MIL-STD-750 Method 1037	15Kcy / ΔTj ≥ 100°C	3	77	231	0/77/3	1 lot / vehicle

#### 3.3. ACCELERATED LIFETIME SIMULATION TESTS

Test	Reference	STM Test Conditions	Lots	S.S.	Total	Results FAIL/SS/Lots	Comments
HTRB	JESD22A-108	1000h @ Tj= 175°C	-	-	-	-	Not applicable
HTGB	JESD22A-108	1000h @ Tj= 175°C	-	-	-	-	Not applicable

#### 3.4. ELECTRICAL VERIFICATION TESTS

Test	Reference	STM Test Conditions	Lots	S.S.	Total	Results FAIL/SS/Lots	Comments
TEST	User specification or supplier's standard specification		3	308	924	0/308/3	
PV	All parameters according to user specification		-	-	-	-	Not applicable
External Visual	JESD22B-101	All devices submitted for testing	3	308	924	0/308/3	
ESDH	AEC-Q101-001	ESD HBM Characterization	-	-	-	-	Not applicable
ESDM	AEC-Q101-001	ESD CDM Characterization	-	-	-	-	Not applicable

#### 4. REVISION HISTORY

Release	Date	Description
1.0	December 5 <sup>th</sup> , 2024	Full plan covered

## TERMS OF USE

BY ACCEPTING THIS DOCUMENT, YOU AGREE TO THE FOLLOWING TERMS OF USE:

This Document (the "Document") and all information contained herein is the property of STMicroelectronics ("ST"). The Document is believed to be accurate and reliable and is provided solely for the purpose of obtaining general information relating to an ST product. Accordingly, you hereby agree to make use of this Document solely for the purpose of obtaining general information relating to the ST product. You further acknowledge and agree that this Document may not be used in or in connection with any legal or administrative proceeding in any court, arbitration, agency, commission, or other tribunal or in connection with any action, cause of action, litigation, claim, allegation, demand, or dispute of any kind. This Document shall in no event be regarded as a warranty of a certain functionality, condition, or quality of the ST product. Accordingly, you agree that in no event will ST or its affiliates be liable to you for any direct, indirect, consequential, exemplary, incidental, punitive, or other damages, including lost profits, arising from, or relating to your reliance upon or use of this Document. You further acknowledge and agree that the use of this Document in violation of these Terms of Use would cause immediate and irreparable harm to ST which could not adequately be remedied by damages. You therefore agree that injunctive relief is an appropriate remedy to enforce these Terms of Use. Disclosure of this Document to any non-authorized party must be previously authorized by ST only under the provision of a proper confidentiality contractual arrangement executed between ST and you and must be treated as strictly confidential.

At all times you will comply with the following security rules:

- Do not copy or reproduce all or part of this Document
- Keep this Document locked away
- Further copies can be provided on a "need to know basis", Please contact your local ST Sales Office or Document writer

Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgement, including, without limitation, the warranty provisions thereunder.

In that respect, please note that ST products are not designed for use in some specific applications or environments described in above mentioned terms and conditions.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers' products.

ST assumes no responsibility for the consequences of use of such information nor for any infringement of patents or other rights of third parties which may result from its use. No license, express or implied, to any intellectual property right is granted by ST herein.

ST and ST logo are trademarks of ST. All other product or service names are the property of their respective owners.

Information in this Document supersedes and replaces information previously supplied in any prior version of this document.

©2024 STMicroelectronics - All rights reserved